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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 1 of 1

Complete if Known

Application Number	10/731,089
Filing Date	December 10, 2003
First Named Inventor	Shinya SASAGAWA et al.
Art Unit	1765
Examiner Name	Not Assigned Yet
Attorney Docket Number	740756-2676

U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ²	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ³ (if known)			
MA	1	US-6,596,571 B2	07/22/2003	Arao et al.	
MA	2	US-6,646,287 B1	11/11/2003	Ono et al.	
MA	3	US-6,706,544 B2	03/16/2004	Yamazaki et al.	
MA	4	US-6,872,604 B2	03/29/2005	Yamazaki et al.	
MA	5	US-6,933,184 B2	08/23/2005	Arao et al.	
MA	6	US-2001/0041392 A1	11/15/2001	Suzawa et al.	
MA	7	US-2001/0048408 A1	12/06/2001	Koyama et al.	
MA	8	US-2002/0102776 A1	08/01/2002	Yamazaki et al.	
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MA	11	US-2003/0062524 A1	04/03/2003	Kimura	
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MA	13	US-2004/0140472 A1	07/22/2004	Fujimoto et al.	
MA	14	US-2004/0171242 A1	09/02/2004	Monoe et al.	
MA	15	US-2004/0209409 A1	10/21/2004	Monoe et al.	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ²	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
MA	16	Y. MISHIMA et al.; "Improved Lifetime of Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEEE TRANSACTIONS ON ELECTRON DEVICES; 06/01/2002; Vol. 49; No. 6; PP. 981-985	
MA	17	K. OHGATA et al.; "A New Dopant Activation Technique for Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEDM: TECHNICAL DIGEST OF INTERNATIONAL DEVICES MEETING; 12/10/2000; PP. 205-208.	
Examiner Signature	/Maki Angadi/		Date Considered 09/08/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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